Tailoring the performance of graphene-based supercapacitors using topological defects: A theoretical assessment

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ABSTRACT

Graphene-based materials have been proposed as promising electrodes for electric double layer capacitors. Recently, it has been found that one of the limitations of graphene electrodes is the finite quantum capacitance at low applied voltage. In this work, we investigate the impact of having point-like topological defects in graphene on the electronic structure and quantum capacitance. Our results clearly show that the presence of defects, such as Stone Wales, di-vacancies, and di-interstitials, can substantially enhance the quantum capacitance when compared to pristine graphene, which is found to be due to defect-induced quasi-localized states near the Fermi level. In addition, the charging behavior tends to be asymmetric around the neutrality point. We also discuss the possibility of tuning the electronic structure and capacitance through mixtures of these defects. Our findings suggest that graphene-based electrodes with topological defects may demonstrate noteworthy capacitance but should be carefully selected for use as either the positive or negative electrode.

1. Introduction

Supercapacitors, a class of electrochemical energy storage devices with high power densities and lifetimes [1], have become increasingly ubiquitous in our energy landscape. Yet their energy densities tend to be at least an order of magnitude less than conventional batteries, which has motivated research focused on improving the capacitance [2,3]. Graphene-based materials are attractive candidates as next-generation electrodes for supercapacitors due to their high theoretical specific surface area and electrical conductivity [4–8]. Despite these favorable qualities, practical implementation of these materials has been limited by poor volumetric surface area and/or accessibility to the electrolyte [9–16]. Several reports have demonstrated that doping or functionalization of graphene can enhance the capacitance considerably, which is suggested to be due to a combination of facilitated electrolyte wettability and electrode accessibility, increased electrical conductivity, and possible pseudocapacitance [17–20]. Recently, the electrode capacitance was also demonstrated to be an important factor; for example, the quantum capacitance of graphene has been found to limit performance at low applied potential [21–23]. In the case of nitrogen-doped graphene, the observed improvement in capacitance has been shown to be, in part, due to the enhanced quantum capacitance [24,25]. This can be particularly true when using ionic liquids (ILs), solvent-free electrolytes with large electrochemical windows, as their chemical stabilities may preclude pseudocapacitive behavior [26,27]. Since the quantum capacitance is proportional to the electronic density of states (DOS) [28], it is plausible that other dopants, functional groups, topological defects, adsorbates, and combinations thereof may also modify the electronic structure and thus, the capacitance. Among these, topological defects...
have been readily observed as a consequence of graphene growth conditions or processing by irradiation or chemical treatment [29–32].

In this paper, we examine the impact of topological defects on the electronic structure and quantum capacitance of graphene. To this end, we simulated graphene electrodes with individual point-like topological defects such as Stone Wales, di-vacancies, and di-interstitials at a defect density $n_d = 3 \times 10^{13} \text{ cm}^{-2}$ ($\approx 0.8 \text{ at.\%}$) using density functional theory (DFT). Based on our results, we also discuss how these topological defects can be utilized to improve the overall performance of graphene-based supercapacitors.

2. Computational methods

The atomic and electronic structures of pristine and defective graphene sheets were calculated using DFT within the Perdew-Wang 91 generalized gradient approximation (GGA-PW91) [33], as implemented in the Vienna Ab-initio Simulation Package (VASP) [34]. We employed the projector augmented wave (PAW) method to describe the interaction between ion core and valence electrons [35], and a plane-wave basis set with a kinetic energy cutoff of 400 eV. We used a hexagonal $8 \times 8$ supercell with a GGA-optimized lattice constant of 2.466 Å and a vacuum space of 15 Å in the $z$ direction to avoid interactions with the periodic image. Each supercell has one defect, corresponding to a defect density of 3.0 $\times 10^{13}$ cm$^{-2}$ ($\approx 0.8 \text{ at.\%}$). For the Brillouin zone integration, we used a $(6 \times 6 \times 1)$ Monkhorst-Pack (M-P) $k$-point mesh for geometry optimization and energy calculations and a $(12 \times 12 \times 1)$ M-P $k$-point mesh for electronic structure calculations. Baker charge [37] distributions were calculated using a rectangular $4 \times 8$ supercell with the same lattice constant, vacuum spacing, and $k$-point mesh when both charge neutral and with the injection of one electron or hole. The larger, mixed-defect system was created using a hexagonal $16 \times 16$ supercell with 15 Å of vacuum space; here, $(3 \times 3 \times 1)$ and $(6 \times 6 \times 1)$ M-P $k$-point meshes were used for geometry optimization and electronic structure calculations, respectively.

3. Results and discussion

A variety of topological defects can be found in graphene, including the three types of point-like defects considered here: Stone Wales (SW), di-vacancies (DVs), and di-interstitials (DIS). The most fundamental of these is the SW defect [38], which occurs when a C–C bond rotates in-plane 90° and results in the structure with two tetragons and two heptagons as shown in Fig. 1(a). According to our DFT-GGA calculations, the formation energy $E_f = 5.0$ eV, which is in good agreement with previously reported values ($\approx 5$ eV) [39,40].

DVs in graphene can be created through either the agglomeration of mono-vacancies or the ejection of adjacent C atoms and have been observed using high resolution transmission electron microscopy [30–32]. Fig. 1(b–d) shows three possible DV reconstructions: $V_2$(555–777), $V_2$(5555–6–777), and $V_2$(5–8–5) [29,30]. The predicted $E_f$ of these defects range from 6.7 $< 7.2 < 7.6$ eV for $V_2$(555–777) $<$ $V_2$(5555–6–777) $< V_2$(5–8–5).

DV defects also tend to be stationary with a migration barrier around 7 eV [41]. Mono-vacancies, on the other hand, tend to be mobile (with a barrier of 1–2 eV) [41] and can be annihilated after thermal annealing. We therefore do not consider mono-vacancies in this analysis.

The formation of DIS have been proposed through the adsorption of C–C dimers, which results in local corrugations or so-called hillocks [42,43]. Fig. 1(e–g) shows three minimum-energy DI structures considered: the inverse SW $I_2$(ISW), $I_2$(555–6–777), and $I_2$(5555–6–777). The $E_f$ of these defects are predicted to range from 6.2 $< 6.6 < 7.3$ eV for $I_2$(ISW) $<$ $I_2$(555–6–777) $< I_2$(5555–6–777). Similar to DVs, DI defects are also expected to be fairly stationary, although single C adatoms have been predicted to be mobile with a barrier of 0.4–0.9 eV [44,45].

3.1. Defect-induced modification of electronic structure

We calculated the electronic band structure and density of states (DOS) of each of the fully relaxed defects using DFT. Point-like topological defects locally reconstruct the lattice and thereby reduce the six-fold symmetry of graphene ($D_{6h}$) to either twofold ($D_{2h}$ or $C_{3v}$) or threefold ($D_{3h}$ or $C_{4v}$) symmetry. The high symmetry lines along the $Γ$–K–M–Γ Brillouin zone (BZ) path are usually sufficient to represent the important features of the band structure for six- and three-fold symmetries. However, the two $K_1$/$K_2$ and $M_1$/$M_2$ are no longer symmetric in the case of twofold symmetry [Fig. 2]. We therefore compare the extended $Γ$–K–M–Γ Brillouin zone (BZ) path for each defect, despite the redundancy in the threefold cases.

Fig. 3 shows the band structure [left] and DOS [middle] of the SW defect (black) compared to pristine graphene (red, dashed). In the latter case, the valence (VB) and conduction (CB) bands display linear dispersion that extends about 1 eV. In the SW case, however, the bands near the Fermi level ($E_F$) are partially flattened; this effect is more marked around 0.45 and 0.60 eV above $E_F$ and gives rise to the distinct peaks in the DOS that are a well-known characteristic of the SW defect [36,47]. These flat bands are indicative of the quasi-localization of the $p_z$ states in the vicinity of the SW defect, due to the disruption of the graphene $π$ system. Hence, injected charge carriers, especially electrons, will accumulate near the pentagon–heptagon C rings, as seen from the band decomposed charge density isosurfaces [right]. However, the flat bands are also smoothly connected to the low-energy dispersion of graphene (more so in the filled states), which suggests that a large fraction of the excess charge can also widely spread over the graphene lattice.

Fig. 4 shows the band structures [left] and DOS [middle] for each of the DV structures. In all three cases, the $E_F$ is shifted down below the VB of graphene primarily due to electron deficiency; note that $V_2$ removes two electrons from the $π$ system of graphene. The DOS plots show several pronounced peaks near the $E_F$ which correspond to partial flattening of the bands, in good agreement with previous work [45,46]. This is apparently attributed to the quasi-localized $p_z$ states in the vicinity of the DV defects, as also depicted in the band decomposed charge density isosurfaces. The degree of localization, however, tends to successively decrease in the $V_2$(555–777), $V_2$(5555–6–777), and $V_2$(5–8–5) cases; this is well demonstrated.
by the increased dispersion of the corresponding bands and the broadening of the DOS peaks within 0.5 eV below $E_F$. The difference in localization tendency amongst the DV configurations is likely related to the relative stability of the coupling of the $p_z$ states in the defect region. In addition, the increased coupling of the quasi-localized $p_z$ states in the $V_2(555-777)$ > $V_2(5555-6-7777)$ > $V_2(5-8-5)$ cases is reflected by the respective decrease in $E_F$ and increase in the shift of $E_F$ from that of graphene [Fig. S1].

The band structures [left] and DOS [middle] for each of the DIs are presented in Fig. 5. Here, the introduction of the C–C dimer creates defect states near $E_F$, rather than adding two electrons into the $\pi$ system of graphene and shifting the $E_F$ above the CB. Furthermore, the graphene lattice is distorted and forms so-called hillocks in each of these cases, thereby disrupting the graphene $\pi$ system. Depending on the defect type, the additional $p_z$ states tend to be partially coupled to the graphene $\pi$ bands as seen in the $I_2(ISW)$ and $I_2(5555-6-7777)$ cases or highly localized such as in the $I_2(555-6-777)$ case. Comparing the former two cases, we observe that the dispersion of the bands is reduced (or the DOS peaks are sharpened) within 0.6 eV of $E_F$ in the $I_2(5555-6-7777)$ case, suggesting that a greater fraction of $p_z$ states are quasi-localized as a result of the greater extent in lattice disorder. In the $I_2(555-6-777)$ case, the partially filled flat bands (or sharp DOS peaks) at $E_F$ are primarily attributed to the $sp^3$-like dangling bonds and $p_z$ orbitals of the hillock C atoms. Similarly, such flat bands at $E_F$ have been identified in zigzag graphene nano-ribbons (GNR) in large association with the $sp^2$-like dangling bonds [48]. These results suggest that upon electron (hole) injection, the quasi-localized states in the vicinity of the defect are preferentially filled (emptied).

### 3.2. Impact of topological defects on capacitance

The quantum capacitance of graphene-based electrodes is defined as $C_Q = \frac{d\rho}{d\phi_C}$, where $d\rho$ and $d\phi_C$ refer to the variations of charge density and local potential in graphene, respectively, and is given by [23]:

$$C_Q = e^2 \int_{-\infty}^{+\infty} D(E)F_T(E - \mu)dE$$

where $D(E)$ is the DOS, $F_T(E)$ is the thermal broadening function $[\pi(\hbar k T)^{-1/2}\exp(\hbar^2 E/2kT)]$, $E$ is the relative energy with respect to $E_F$, $\mu$ is the chemical potential ($=e\phi_C$), and $e$ is the elementary charge.

Fig. 6 shows the calculated $C_Q$ for pristine [(a)] and each of the defective [(b–h)] graphene electrodes at 300 K, which tend to resemble their respective DOS profiles under thermal broadening. In Fig. 6(a), we observe that the $C_Q$ of pristine...
graphene is zero at $\phi_C = 0$ V where the Dirac cone is located but increases linearly to around 250 F/g at $\phi_C = \pm 1$ V. In contrast, all of the defective graphene sheets tend to have highly irregular $C_Q$ profiles with local sharp enhancements close to the neutrality point; these peaks correspond to the aforementioned quasi-localized $p_z$ states.

In Fig. 7, we show $\sigma$ as a function of $\phi_C$ to represent the cumulative excess charge in the electrode at a given electrode potential. The defective graphene electrodes generally store more charge than pristine graphene within the 2 V window presented here, although the $V_2(555-777)$ case is the exception beyond $\phi_C < 0.75$ V. This increased charge capacity is a direct consequence of the additional availability of states near $E_F$. In other words, to achieve the same electrode charge density, a lower $\phi_C$ is required for the defective graphene electrodes. However, it is also evident that these electrodes no longer store charge symmetrically. As a result, certain defect types are better suited for different terminals; the SW case, for example, is clearly more effective as a negative electrode while the $V_2(555-777)$, $V_2(5555-6-7777)$, and $I_2(ISW)$ cases are more effective as positive electrodes.

Along with $C_Q$, the electric double layer (EDL) capacitance ($C_D$) will also influence the total interfacial capacitance ($C_T$), which is given by $1/C_T = 1/C_Q + 1/C_D$. The EDL capacitance is evaluated based on the microstructure of the electrolyte near the electrode under applied potential and has been studied using computational methods for a variety of ILs near pristine graphene [23,49–54]. However, the presence of defects affects the charge distribution along the electrode surface, which in turn may influence the IL arrangement near the surface. For example, our previous work [25] with nitrogen-doped graphene at 2.7 at.% showed that the maximum (minimum) atomic charge near the defect sites was 0.66 ($\geq 0.25$) when $\phi_C = 5.43 \mu C/cm^2$. Yet, the N-doping was found to have little influence on the EDL microstructure and capacitance.

According to Bader charge analysis [Fig. S2], the injection of one electron or hole into the defect lattice with $n_d = 3 \times 10^{13}$ cm$^{-2}$ ($\approx 0.8$ at.%) is spread broadly, with a maximum (minimum) atomic charge of 0.20 ($\leq 0.25$) $e$ on select atoms. Given that the charge distribution exhibits smaller fluctuations compared to the N-doped case, we can expect that these small point-like topological defects will also have a marginal effect on $C_D$ (see Fig. S3 in Supporting Information). We should note that in the DI cases, the curvature of the hillocks could additionally affect $C_D$; previous studies have demonstrated that $C_D$ improves with increasing electrode curvature [55–57] or surface roughness [58,59]. However, we can expect the effect of surface topology on $C_D$ to also be marginal since the hillocks are both isolated and have small curvature. In short, the $C_D$ using graphene electrodes with the considered topological defects is likely similar to that of pristine graphene electrodes, although this may not be the case when we consider larger concentrations of defects or larger-scale defects. We therefore expect $C_T$ to correspondingly increase due to the enhanced $C_Q$ (possible $C_D/C_T$ profiles are shown in Figs. S4 and S5 in Supporting Information), which is similarly demonstrated in the case of N-doping [18,24,25]. To the best of our knowledge, comparisons to experimental results are not possible at this time since the (differential) $C_T$ of supercapacitors using graphene with topological defects has never been reported. But we
should also note that our quantitative results may require further refinement. For instance, we have neglected the possible polarization of the electrodes [53] and IL ions at the interface and its effects on the electrode charge redistribution, the space charge density, and subsequently, $C_D$. In addition, the DOS (and $C_Q$) may be altered to a certain extent if the electronic structure is locally modified by electrode–IL interactions, which were omitted for simplicity. Nonetheless, our analysis clearly shows that topological defects can have a profound impact on, and likely improve, $C_Q$ and thus, $C_T$.

### 3.3. Tuning the electronic structure and quantum capacitance using topological defects

In Section 3.2, we presented the electronic structure and $C_Q$ of individual topological defects. Experimentally, however, it may be quite challenging to recreate such homogeneity along the graphene lattice. Therefore in Section 3.3, we increase the complexity by exploring the impact of having different combinations of topological defects on the electronic structure and $C_Q$. To this end, we have simulated two scenarios: graphene sheets with an overall $n_d = 3 \times 10^{13} \text{ cm}^{-2}$ using (1) SW, V$_2$(555-777), $\text{I}_\text{SW}$, I$_2$(555-6-777), and I$_2$(5555-66-7777) defects [Fig. 8(a)] and (2) V$_2$(555-777) and I$_2$(5555-66-7777) defects at a 3:1 ratio [Fig. 8(b)].

Fig. 8(a and b) show the DOS of each of the respective configurations of defective graphene sheets, which exhibit several sharp peaks near $E_F$. According to our analysis of the projected DOS [Fig. S6], each of these peaks is attributed to a particular defect-induced quasi-localized state (see markings), which has been similarly observed in previous theoretical work [46,60]. Note that the positions of these quasi-localized states relative to each other remain largely unchanged; the position of $E_F$ is approximated by the (density-weighed) average positions of each $E_F$ in the associated individual defect cases (which can be possible when long-range coupling between adjacent defect types is absent; see Figs. S7 and S8 for further discussion). This analysis implies that the following two-step process can be used to tailor the electronic structure of defective graphene: (1) determine the relative positions of quasi-localized states from the chosen array of topological defects and (2) shift the position of $E_F$ based on the densities of each topological defect. However, this procedure is likely possible only when defect states are both relatively close in energy and coupled to the $\pi$ system; without these conditions, gaps in the DOS would appear between the localized states.

Fig. 8(a and b) also depict the predicted $C_Q$ of the mixed defect electrodes at 300 K. We additionally plot $\sigma$ as a function of $\phi$ in the insets. Similar to the individual defect cases, while $\sigma$ tends to be larger than that of pristine graphene, the predicted enhancement will vary between the positive and negative terminal. In fact in both cases, a larger $\sigma$ is favored at the positive electrode. This suggests that graphene electrodes can be individually tailored for operation as either the...
positive or negative electrode; the use of asymmetric electrodes for supercapacitors has the potential to significantly increase performance and deserves further investigation.

4. Conclusion

We have investigated the impact of topological defects on the electronic structure and quantum capacitance of graphene using density functional theory. In this study, we considered small point-like defects such as Stone-Wales, divacancies, and di-interstitials. The presence of these defects disrupts the π system of graphene, which gives rise to quasi-localized states of varying degrees near the Fermi level. As a result, each of these defective graphene electrodes tends to have enhanced quantum capacitance compared to pristine graphene, while the double layer capacitance tends to remain virtually unaffected by the presence of these small SW, V₂, and I₂ defects considered. Interestingly, their charging behavior is found to be asymmetric around the neutrality point such that some defective graphene sheets are more effective as either the positive or negative electrode. Our analysis also suggests that the double layer capacitance remains virtually unaffected by the presence of these defects. These findings indicate that graphene electrodes with topological defects may be used to enhance the overall capacitance of supercapacitors by virtue of the increased quantum capacitance. Furthermore, our study suggests that graphene-based electrodes can be specifically tailored as separate positive and negative electrodes, which could significantly enhance the performance of supercapacitors and warrants further study.

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Appendix A. Supplementary data

Supplementary data associated with this article can be found, in the online version, at http://dx.doi.org/10.1016/j.carbon.2013.11.057.

References


